TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74VHC125F,TC74VHC125FN,TC74VHC125FT,TC74VHC125FK TC74VHC126F,TC74VHC126FN,TC74VHC126FT,TC74VHC126FK

TC74VHC125F/FN/FT/FK Quad Bus Buffer TC74VHC126F/FN/FT/FK Quad Bus Buffer

The TC74VHC125/126 are high speed CMOS QUAD BUS BUFFERs fabricated with silicon gate C²MOS technology.

They achieve the high speed operation similar to equivalent Bipolar Shottky TTL while maintaining the CMOS low power dissipation.

The TC74VHC125 requires the 3-state control input \overline{G} to be set high to place the output into the high impedance state, whereas the TC74VHC126 requires the control input G to be set low to place the output into high impedance.

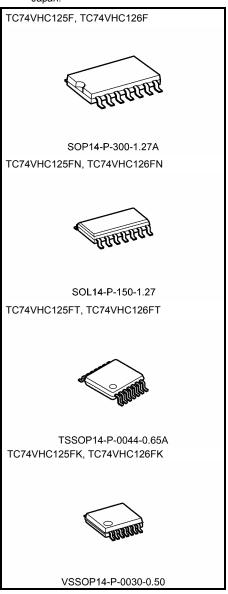
An input protection circuit ensures that 0 to 5.5~V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5~V to 3~V systems and two supply systems such as battery back up.

This circuit prevents device destruction due to mismatched supply and input voltages.

Features

- High speed: $t_{pd} = 3.8 \text{ ns (typ.)}$ at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 4 \mu A$ (max) at $T_a = 25$ °C
- High noise immunity: V_{NIH} = V_{NIL} = 28% V_{CC} (min)
- Power down protection is provided on all inputs.
- Balanced propagation delays: tpLH ~ tpHL
- Wide operating voltage range: VCC (opr) = 2 to 5.5 V
- Low noise: VOLP = 0.8 V (max)
- Pin and function compatible with 74ALS125/126

Note: xxxFN (JEDEC SOP) is not available in Japan.

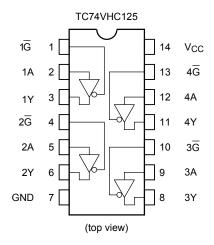


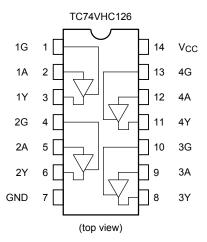
Weight

SOP14-P-300-1.27A : 0.18 g (typ.) SOL14-P-150-1.27 : 0.12 g (typ.) TSSOP14-P-0044-0.65A : 0.06 g (typ.) VSSOP14-P-0030-0.50 : 0.02 g (typ.)

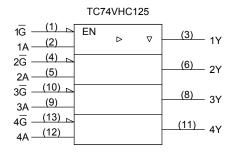


Pin Assignment





IEC Logic Symbol



	TC7	4VHC	126	
1G (1) 1A (2)	EN	D	∇	(3) 1Y
2G — (4) 2A — (5)	-			(6) 2Y
3G <u>(10)</u> 3A <u>(9)</u>				(8) 3Y
4G (13) 4A (12)				(11) 4Y

Truth Table

TC74VHC125

Inputs		Output
Ġ	Α	Y
Н	Χ	Z
L	L	L
L	Н	Н

X: Don't care

Z: High impedance

TC74VHC126

Inputs		Output
G	Α	Y
L	Х	Z
Н	L	L
Н	Н	Н

X: Don't care

Z: High impedance



Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	−0.5 to 7.0	V
DC input voltage	V _{IN}	−0.5 to 7.0	٧
DC output voltage	V _{OUT}	-0.5 to V_{CC} + 0.5	V
Input diode current	I _{IK}	-20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V _{cc} /ground current	Icc	±50	mA
Power dissipation	PD	180	mW
Storage temperature	T _{stg}	–65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit	
Supply voltage	V _{CC}	2.0 to 5.5	V	
Input voltage	V _{IN}	0 to 5.5	V	
Output voltage	V _{OUT}	0 to V _{CC}	V	
Operating temperature	T _{opr}	-40 to 85	°C	
Input rise and fall time	dt/dv	0 to 100 (V _{CC} = 3.3 ± 0.3 V)	ns/V	
input rise and rail time	avav	0 to 20 ($V_{CC} = 5 \pm 0.5 \text{ V}$)		

Note: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either VCC or GND.



Electrical Characteristics

DC Characteristics

Characteristics Symbol		Test Condition		Ta = 25°C			Ta = -40 to 85°C		Unit	
			V		Min	Тур.	Max	Min	Max	0
High-level input				2.0	1.50	_	_	1.50	_	
voltage	V _{IH}	_		3.0 to 5.5	V _{CC} × 0.7	_	_	V _{CC} × 0.7	_	V
Low-level input				2.0	_	_	0.50	_	0.50	
voltage	V _{IL}		_	3.0 to 5.5	_	_	V _{CC} × 0.3	_	V _{CC} × 0.3	V
				2.0	1.9	2.0	_	1.9	_	
	V _{OH}	V _{IN} = V _{IH} or V _{IL}	$I_{OH} = -50 \ \mu A$	3.0	2.9	3.0	_	2.9	_	
High-level output voltage				4.5	4.4	4.5	_	4.4		V
			$I_{OH} = -4 \text{ mA}$	3.0	2.58	_	_	2.48		
			$I_{OH} = -8 \text{ mA}$	4.5	3.94	_	_	3.80	_	
	V _{OL}	VIN = VIH or VIL		2.0	_	0.0	0.1		0.1	
			$I_{OL} = 50 \ \mu A$	3.0	_	0.0	0.1	_	0.1	
Low-level output voltage				4.5	_	0.0	0.1	_	0.1	V
			$I_{OL} = 4 \text{ mA}$	3.0	_	_	0.36		0.44	
			$I_{OL} = 8 \text{ mA}$	4.5	_	_	0.36	_	0.44	
3-state output off-state current	I _{OZ}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_		±0.25	_	±2.50	μΑ
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5			±0.1	_	±1.0	μА
Quiescent supply current	Icc	V _{IN} = V _{CC} or	GND	5.5	_	_	4.0		40.0	μА



AC Characteristics (input: $t_r = t_f = 3$ ns)

Characteristics Symbol		Test Condition			Ta = 25°C			Ta = -40 to 85°C		Unit
	,		V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Min	Max	
			3.3 ± 0.3	15	_	5.6	8.0	1.0	9.5	
Propagation delay	t_{pLH}			50	_	8.1	11.5	1.0	13.0	
time	t_{pHL}	_	5.0 ± 0.5	15	_	3.8	5.5	1.0	6.5	ns
			5.0 ± 0.5	50	_	5.3	7.5	1.0	8.5	
			3.3 ± 0.3	15	_	5.4	8.0	1.0	9.5	- ns
Output enable time	^t pZL ^t pZH	$R_L = 1 \text{ k}\Omega$	3.3 ± 0.3	50	_	7.9	11.5	1.0	13.0	
Output enable time			5.0 ± 0.5	15	_	3.6	5.1	1.0	6.0	
				50	_	5.1	7.1	1.0	8.0	
Output disable time	t_{pLZ}	$R_L = 1 \text{ k}\Omega$	3.3 ± 0.3	50	_	9.5	13.2	1.0	15.0	ns
Output disable time	t_{pHZ}		5.0 ± 0.5	50	_	6.1	8.8	1.0	10.0	115
Output to output skew	t _{osLH}	(Note 1)	3.3 ± 0.3	50	_	_	1.5		1.5	ne
Output to output skew	t _{osHL}	(Note 1)	5.0 ± 0.5	50	_	_	1.0	_	1.0	ns
Input capacitance	C _{IN}		_		_	4	10	_	10	pF
Output capacitance	C _{OUT}		_		_	6	_	_	_	pF
Power dissipation capacitance (Note 2)	0	TC74VHC125 TC74VHC126		_	14	_	_	_	n.E	
	C _{PD}					15		_	_	pF

Note 1: Parameter guaranteed by design.

$$t_{\text{osLH}} = |t_{\text{pLHm}} - t_{\text{pLHn}}|, \, t_{\text{osHL}} = |t_{\text{pHLm}} - t_{\text{pHLn}}|$$

Note 2: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

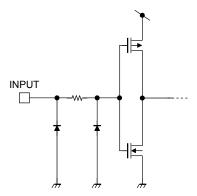
$$I_{CC \text{ (opr)}} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4 \text{ (per gate)}$$

Noise Characteristics (input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition		Ta = 25°C		Unit
Characteristics	Symbol		V _{CC} (V)	Тур.	Limit	OTIL
Quiet output maximum dynamic VoL	V _{OLP}	C _L = 50 pF	5.0	0.3	0.8	٧
Quiet output minimum dynamic VOL	V _{OLV}	C _L = 50 pF	5.0	-0.3	-0.8	V
Minimum high level dynamic input voltage	V_{IHD}	C _L = 50 pF	5.0	_	3.5	V
Maximum low level dynamic input voltage	V _{ILD}	C _L = 50 pF	5.0		1.5	V



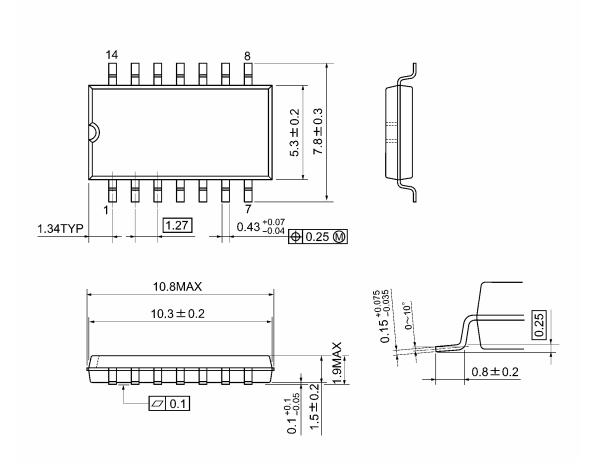
Input Equivalent Circuit



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Package Dimensions

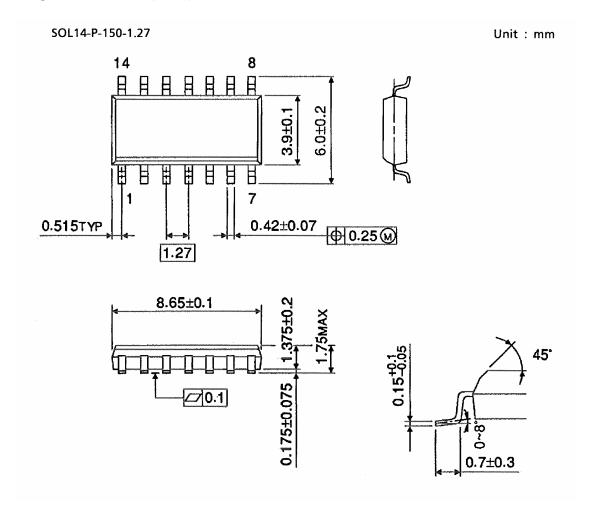
SOP14-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)



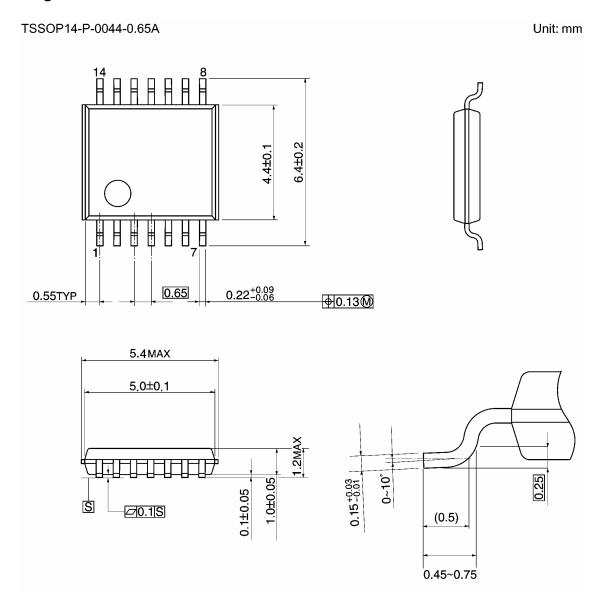
Package Dimensions (Note)



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

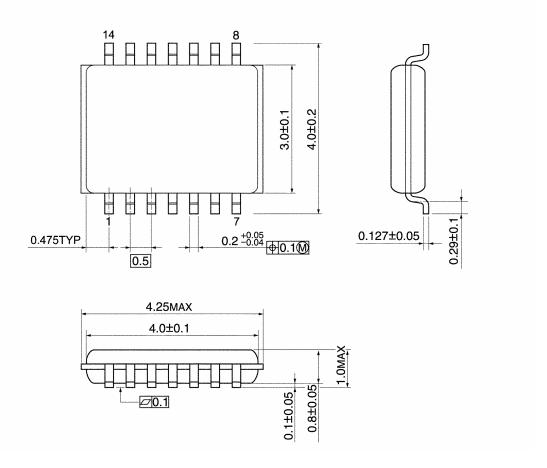
Package Dimensions



Weight: 0.06 g (typ.)

Package Dimensions

VSSOP14-P-0030-0.50 Unit: mm



Weight: 0.02 g (typ.)

RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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